-OP \$320.00 1182321

PATENT ASSIGNMENT

Electronic Version v1.1 Stylesheet Version v1.1

 SUBMISSION TYPE:
 NEW ASSIGNMENT

 NATURE OF CONVEYANCE:
 ASSIGNMENT

CONVEYING PARTY DATA

| Name | Execution Date |
|--|----------------|
| Tevet Process Control Technologies, Ltd. | 07/03/2008 |

RECEIVING PARTY DATA

| Name: | Nanometrics Incorporated |
|-----------------|--------------------------|
| Street Address: | 1550 Buckeye Drive |
| City: | Milpitas |
| State/Country: | CALIFORNIA |
| Postal Code: | 95035 |

PROPERTY NUMBERS Total: 8

| Property Type | Number |
|---------------------|----------|
| Application Number: | 11823215 |
| Application Number: | 11823452 |
| Application Number: | 11823229 |
| Application Number: | 11717327 |
| Patent Number: | 6678055 |
| Patent Number: | 6762838 |
| Patent Number: | 6801321 |
| Patent Number: | 6885467 |

CORRESPONDENCE DATA

Fax Number: (408)378-7770

Correspondence will be sent via US Mail when the fax attempt is unsuccessful.

Phone: 408-378-7777

Email: mhalbert@svpatentgroup.com

Correspondent Name: Michael J. Halbert Address Line 1: 18805 Cox Avenue

Address Line 2: Suite 220

PATENT REEL: 021194 FRAME: 0642

500585692

| Address Line 4: Saratoga, CALIFORNIA 95070 | | |
|--|--------------------|--|
| ATTORNEY DOCKET NUMBER: | NAN001 | |
| NAME OF SUBMITTER: | Michael J. Halbert | |
| Total Attachments: 3 source=TEVET_Assign#page1.tif source=TEVET_Assign#page2.tif source=TEVET_Assign#page3.tif | | |

PATENT REEL: 021194 FRAME: 0643

אימות חתימה

אני החתום

אריה זטלר עו"ד ונוטריון

בקניון דרכים, רתוב התמר, יקנעם עילית

מאשר כי ביום 3 יולי 2008 ניצב לפני במשרדי

מר משה עופר די-נור ת"ז מסי 053921615 שניתנה ביום 11.05.1997 בעפולה

וחתם מרצונו החופשי על המסמך המצורף באות "A".

ולראיה הנני מאמת את תתימתו של כור משה עופר די-נור ה"ה בחתיכות ידי ובחותמי, היום 03.07.2008.

שכר בסך 140 נה + מע"מ שולם

Authentication of Signature

I, the undersigned.

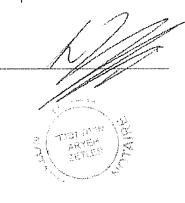
Advocate Aryeh Zetler, Notary,

of Drachim Center, Hatamar Street, Yokneam Elite, Israel

do hereby certify that on 3 July 2008 there appeared before me at my office Mr. Moshe Ofer Du-Nour Israeli identity No. 053921615 issued on 11.05.1997 at Afula and signed the attached document marked "A" of his own free will.

In witness whereof I hereby authenticate the signature of Mr. Moshe Ofer Du-Nour by my signature and seal on 03.07.2008.

Fees in the amount of 140 shekels plus Value Added Tax have been paid.



PATENT REEL: 021194 FRAME: 0644

ASSIGNMENT

For good and valuable consideration, receipt of which is hereby acknowledged, Tevet Process Control Technologies, Ltd., having a place of business at P.O. Box 690 Building 2, AREA 7, Industrial Park, Yokne'am, Israel 20892, having acquired by a prior assignment, the entire right, title, and interest in the inventions for which United States patent applications listed below were filed, some of which have been published as listed below, as well as all patent applications and patents of every country for said inventions, including divisionals, continuations, reissues, reexaminations and extensions thereof, and all rights of priority resulting from the filing of said applications; and having acquired the right to apply for patents of foreign countries for said inventions, and to claim all rights of priority without further authorization:

| Serial No. | Filing Date: | Publ./Pat. No. | Publ/Pat. Date | Title: |
|------------|--------------|----------------|----------------|---|
| 11/823,215 | 06/26/2007 | | | Method and System for Positioning a Metrology Apparatus Method and Apparatus for Measuring |
| 11/823,452 | 06/26/2007 | | | Thickness and Optical Properties of a Thin-Film on a Substrate |
| 11/823,229 | 06/26/2007 | | | Metrology Apparatus for Measuring Multiple Sites in Parallel Method and Apparatus for Process |
| 11/717,327 | 03/12/2007 | 2007/0298522 | 12/27/2007 | Control with In-Die Metrology Method and Apparatus for Measuring |
| 09/991,709 | 11/26/2001 | 6,678,055 | 01/13/2004 | Stress in Semiconductor Waters |
| 09/895,333 | 07/02/2001 | 6,762,838 | 07/13/2004 | Line Screening |
| 09/762,473 | 02/07/2001 | 6,801,321 | 10/05/2004 | Refractive Index of a Transparent |
| 10/281,207 | 10/28/2002 | 6,885,467 | 04/26/2005 | Method and Apparatus for Thicknes Decomposition of Complicated Lay Structures |

hereby sells, assigns and transfers to Nanometrics Incorporated, a Delaware corporation, having a place of business at 1550 Buckeye Drive, Milpitas, CA 95035-7418, its successors and assigns, the entire right, title and interest throughout the world in the inventions for which the assigns, the entire right, title and interest throughout the world in the inventions for which the United States patent applications listed above were filed, some of which have been published, together with any patent applications and patents of every country for said invention, including divisionals, continuations, reissues, reexaminations and extensions or foreign counterparts thereto, and all rights of priority resulting from the filing of said applications; Tevet Process

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PATENT 645 REEL: 021194 FRAME: 0645 Control Technologies, Ltd. agrees to execute all papers useful in connection with said United States and foreign applications, and generally to do everything possible to aid said assignee, its successors, assigns, and nominees, at their request and expense, in obtaining and enforcing patents for said invention in all countries; and Tevet Process Control Technologies, Ltd. requests that the United States Patent and Trademark Office and all foreign patent offices issue all patents granted for said inventions to Nanometrics Incorporated, its successors and assigns.

| Executed this \(\frac{\lambda}{\lambda} \) day of \(| July . 2008. |
|---|--|
| For: Tevet Process Control Techno | ologies, Ltd. |
| | Name: Ofer Du-Nour Title: Chairman of the Board For: Tevet Process Control Technologies, Ltd. |
| State of | 88. |
| Onbei | personally appeared proved to me on the basis of satisfactory evidence to be the person assument and acknowledged to me that he executed the same in his ture on the instrument the person, or the entity upon behalf of which the |
| | WITNESS my hand and official seal. |
| | SIGNATURE OF NOTARY |

Page 2 of 2

RECORDED: 07/07/2008

